

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of: Ikeuchi, Katsushi et al.	)	Group Art Unit: 2859
	)	
Application No.: 10/598,010	)	Examiner: Sheela C. Chawan
	)	
Filed: May 2, 2007	)	
	)	
For: Shape Measurement Device and	)	
Method Thereof	)	
	)	

**RESPONSE TO OFFICE ACTION BY SUBMISSION OF RULE 131 AFFIDAVIT  
AND SUPPORTING EVIDENCE**

Mail Stop Patent Application  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Sir:

Please amend the accompanying patent application as follows:

**Arguments and Remarks** begin on page 2 of this submission.